


<b>Search Notes</b>  	<b>Application/Control No.</b>  10781354	<b>Applicant(s)/Patent Under Reexamination</b>  DICKEN, VOLKER
	<b>Examiner</b>  Hajnik, Daniel F	<b>Art Unit</b>  2628

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Update search conducted in EAST; NPL search conducted in ACM, Google, and IEEE, search terms include voxel, distance fields, 2D, and projection	8/20/08	DFH
EAST text search (US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB -- see search history printout)	8/20/08	DFH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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Examiner,Art Unit 2628